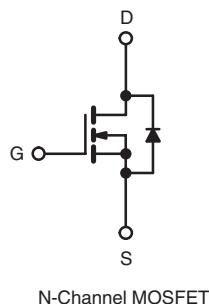
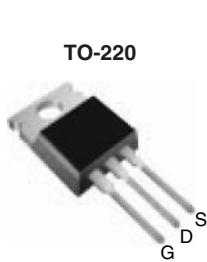


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	600
R _{D(on)} (Ω)	V _{GS} = 10 V 2.2
Q _g (Max.) (nC)	23
Q _{gs} (nC)	5.4
Q _{gd} (nC)	11
Configuration	Single



FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective C_{oss} Specified
- Lead (Pb)-free Available


RoHS*
COMPLIANT

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGY

- Single Transistor Flyback

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRFBC30APbF SiHFBC30A-E3
SnPb	IRFBC30A SiHFBC30A

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	600	
Gate-Source Voltage		V _{GS}	± 30	V
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I _D	A
		T _C = 100 °C	2.3	
Pulsed Drain Current ^a		I _{DM}	14	
Linear Derating Factor			0.69	W/°C
Single Pulse Avalanche Energy ^b		E _{AS}	290	mJ
Repetitive Avalanche Current ^a		I _{AR}	3.6	A
Repetitive Avalanche Energy ^a		E _{AR}	7.4	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	74	W
Peak Diode Recovery dV/dt ^c		dV/dt	7.0	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6-32 or M3 screw		10	lbf · in
			1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Starting T_J = 25 °C, L = 41 mH, R_G = 25 Ω, I_{AS} = 3.6 A (see fig. 12).

c. I_{SD} ≤ 3.6 A, dI/dt ≤ 170 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

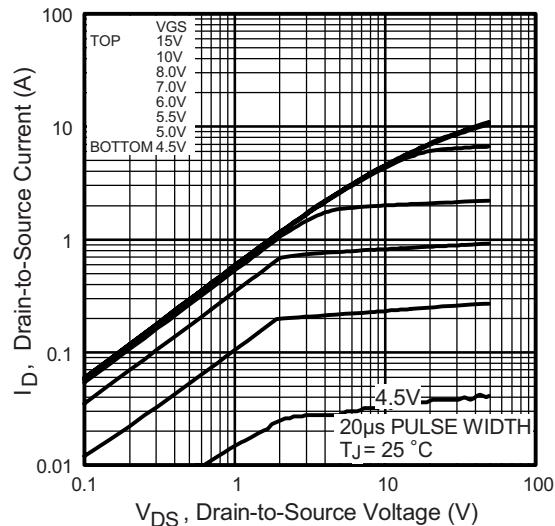
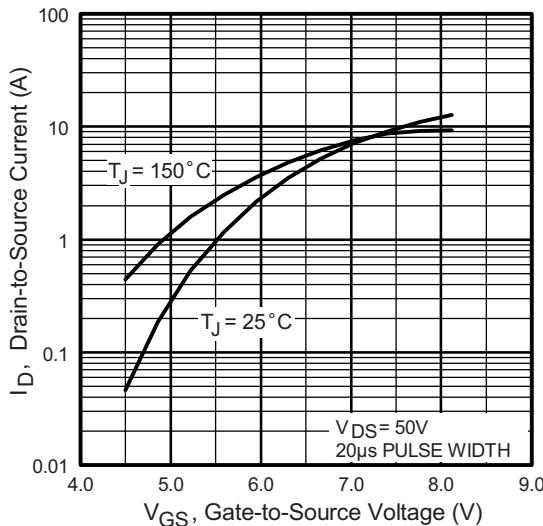
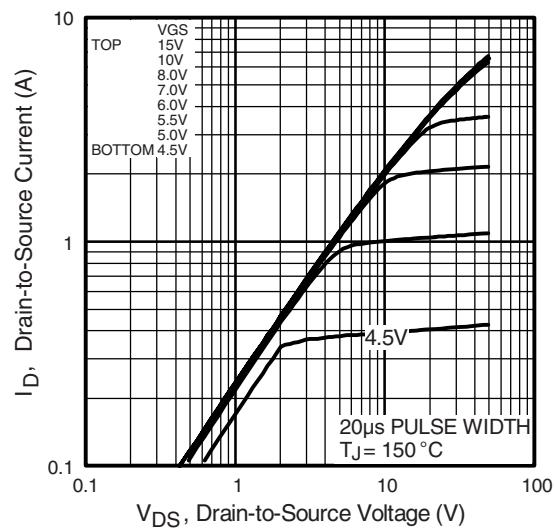
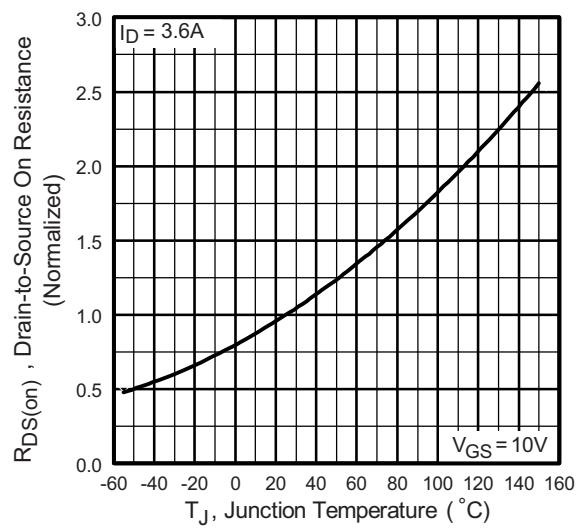
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.7	

SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	600	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$		-	0.67	-	$^{\circ}\text{C}/\text{V}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.5	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA
		$V_{DS} = 480 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125 \text{ }^{\circ}\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 2.2 \text{ A}^b$	-	-	2.2	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 2.2 \text{ A}^b$		2.1	-	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	510	-	pF
Output Capacitance	C_{oss}			-	70	-	
Reverse Transfer Capacitance	C_{rss}			-	3.5	-	
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	730	-	pF
			$V_{DS} = 480 \text{ V}$, $f = 1.0 \text{ MHz}$	-	19	-	
Effective Output Capacitance	$C_{oss eff.}$		$V_{DS} = 0 \text{ V}$ to 480 V^c	-	31	-	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 3.6 \text{ A}$, $V_{DS} = 480 \text{ V}$ see fig. 6 and 13 ^b	-	-	23	nC
Gate-Source Charge	Q_{gs}			-	-	5.4	
Gate-Drain Charge	Q_{gd}			-	-	11	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 300 \text{ V}$, $I_D = 3.6 \text{ A}$, $R_G = 12 \Omega$, $R_D = 82 \Omega$, see fig. 10 ^b		-	9.8	-	ns
Rise Time	t_r			-	13	-	
Turn-Off Delay Time	$t_{d(off)}$			-	19	-	
Fall Time	t_f			-	12	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.6	A
Pulsed Diode Forward Current ^a	I_{SM}			-	-	14	
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_S = 3.6 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.6	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_F = 3.6 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	400	600	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	1.1	1.7	μC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.
c. $C_{oss eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFBC30A, SiHFBC30A

Vishay Siliconix

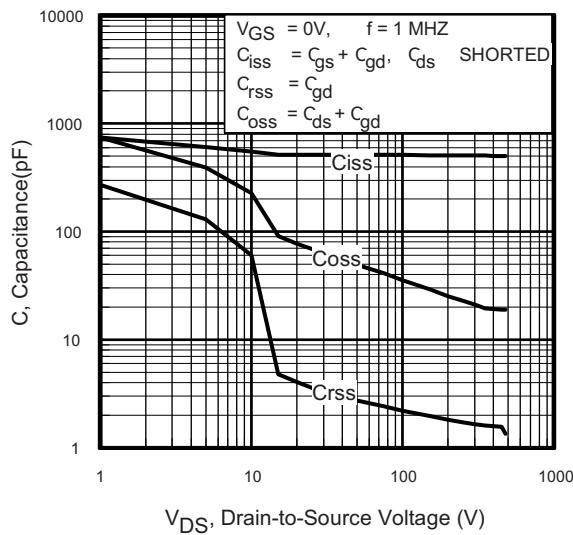


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

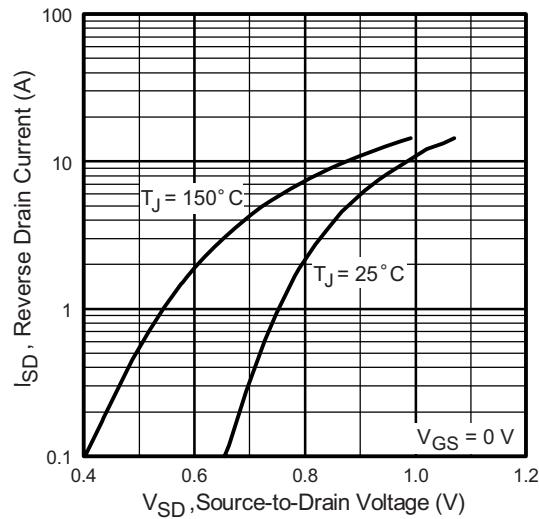


Fig. 7 - Typical Source-Drain Diode Forward Voltage

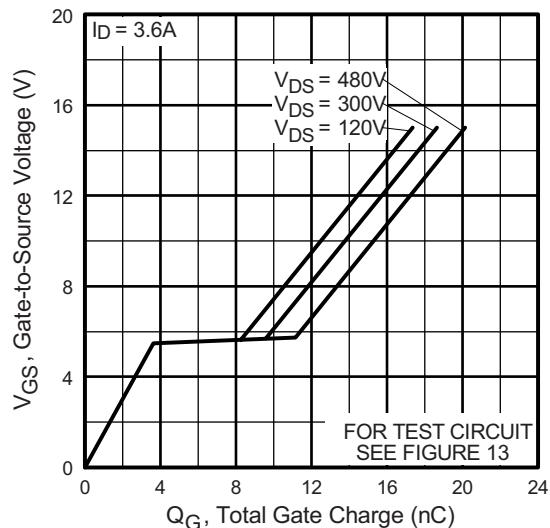


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

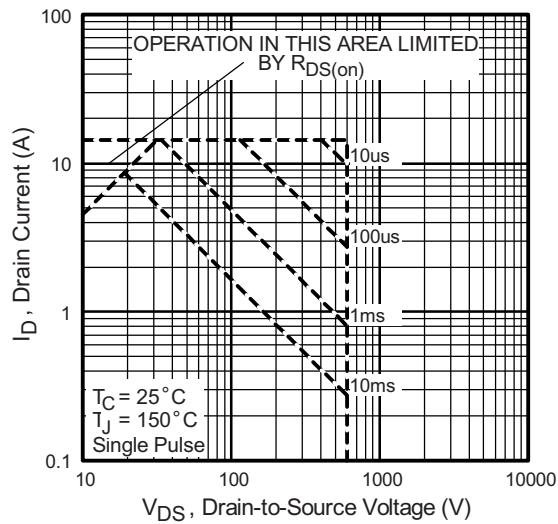


Fig. 8 - Maximum Safe Operating Area

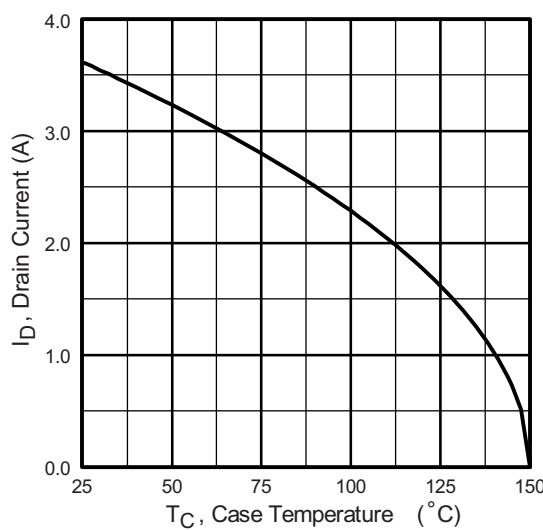


Fig. 9 - Maximum Drain Current vs. Case Temperature

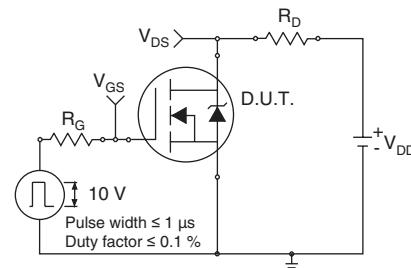


Fig. 10a - Switching Time Test Circuit

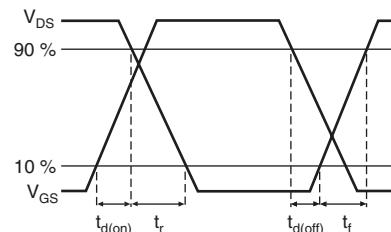


Fig. 10b - Switching Time Waveforms

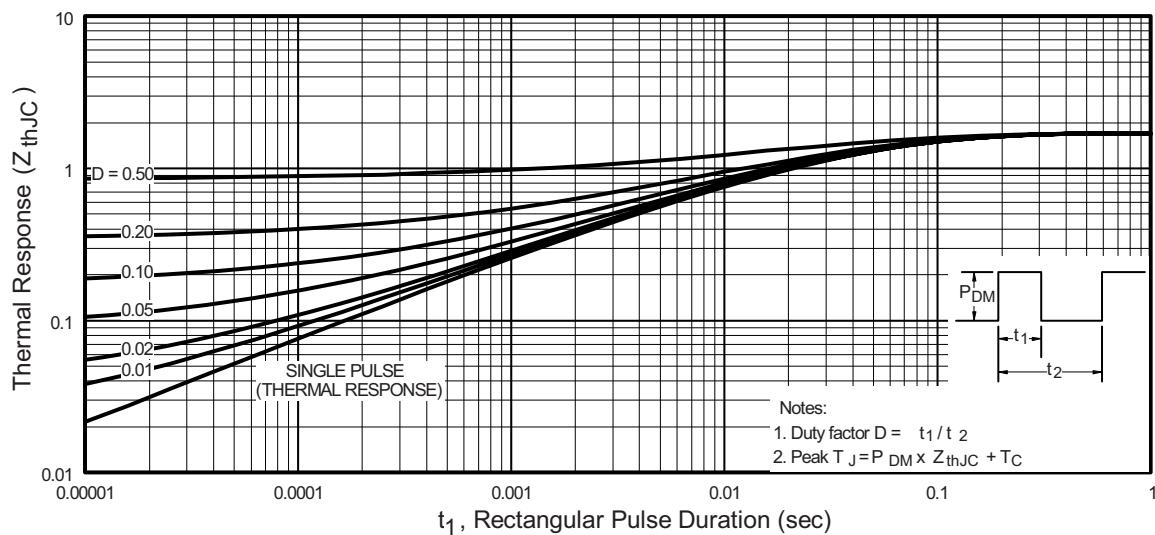


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

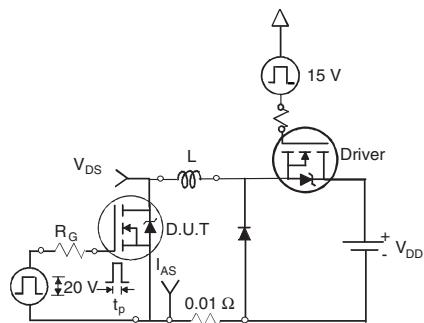


Fig. 12a - Unclamped Inductive Test Circuit

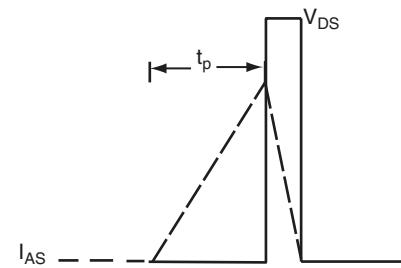


Fig. 12b - Unclamped Inductive Waveforms

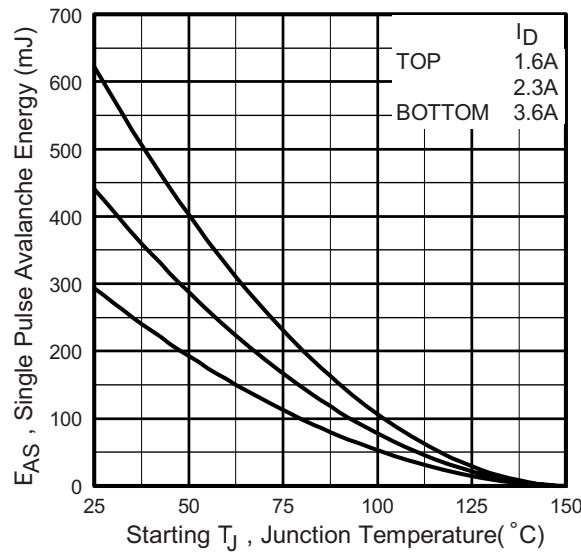


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

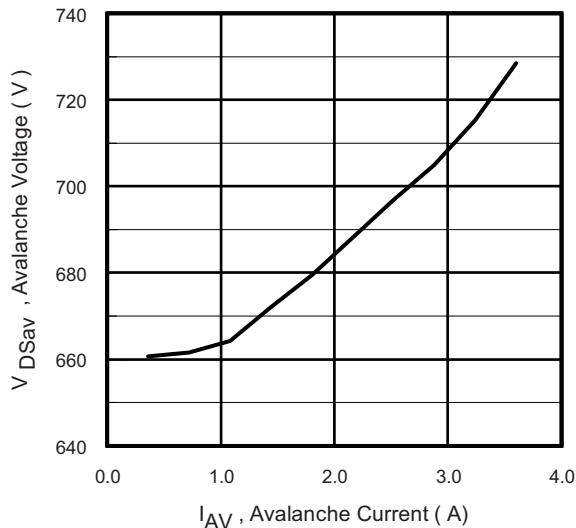


Fig. 12d - Typical Drain-to-Source Voltage vs. Avalanche Current

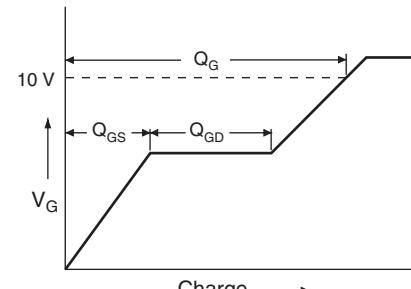


Fig. 13a - Basic Gate Charge Waveform

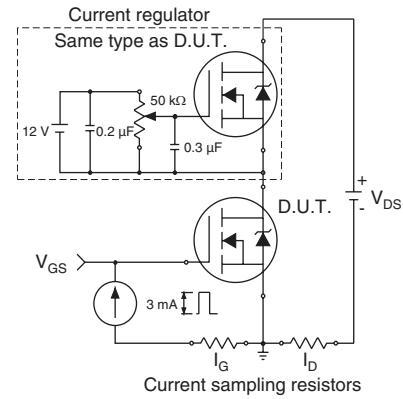
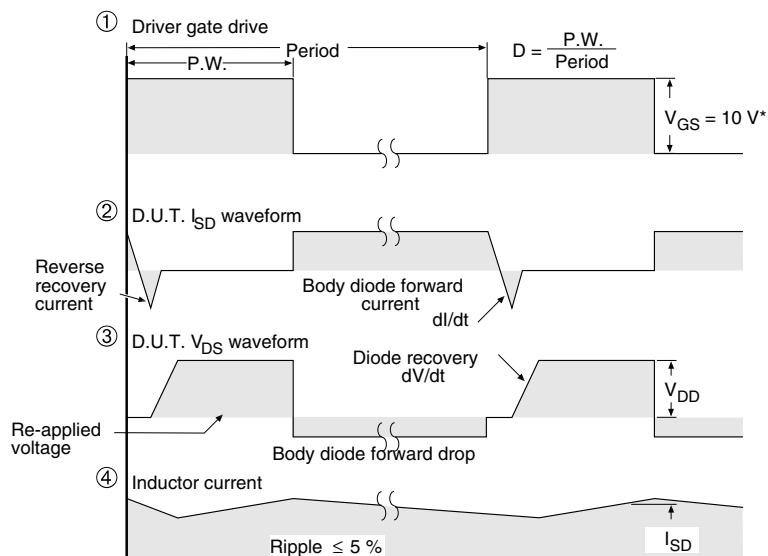
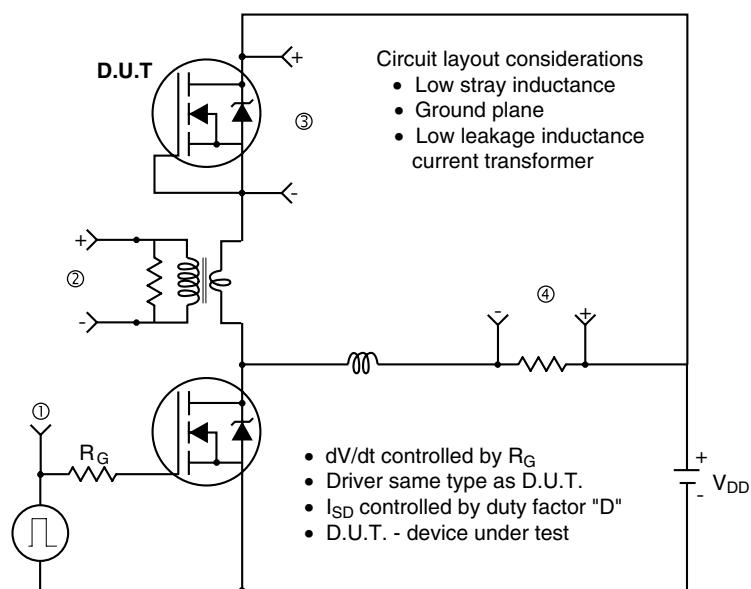


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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